

Upcoming Conference Call

- **Outline and Tasks:**

- Programmatic: *Action Items for Geoff Brennecka, with all*
 - *schedule conference call between March 1 and Mar 12 (by Feb 22)*
 - *finalize all student hiring and related logistics (before call)*
 - *disseminate information about uploading updates and connecting to call (by Feb 26)*
- IL + BCP: *Action Item for Charlie Liu, with UNM - update on following (>24 hrs before call)*
 - Equipment status
 - Large-area pattern quality with optimized ARC
 - Density multiplication
 - Process improvements associated with brush layer, PR removal, trim, etc.
- BCP + NIL: *Action Item for Jack Skinner, with UW - update on following (>24 hrs before call)*
 - Improved etch processes for optimal nanofeature profile
 - Progress towards initial plasmonic device test platform
- Modeling and Simulation: *Action Items for Darin Pike and/or Juan de Pablo*
 - *Update on effects of interface(s) on equilibrium morphologies and annealing dynamics (>24hrs before call)*
 - *Determine if any additional students from your group will be involved in the project; if so, identify them (ASAP)*
 - *Determine who, if anyone, will be working at SNL during 2010 and discuss with Geoff (ASAP)*
- Metrology: *Action Item for Bruce Burckel, with all - update on following (>24 hrs before call)*
 - Image analysis for CD, LER, etc.
 - Project-wide standard die? yes/no, if yes give details for implementation
 - Diagram process flow including local iterations showing required/optional measurement points

